CITATION

PTO-1449

Applicant

CAI, Lynn

Filing Date

2/13/2002

CA23

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EXAMINER'S INITIALS

Lin. B.J., et al., "Single-Level Electric Testsites for Phase-Shifting Masks", SPIE, Vol. 1673, pp. 221-228, March 9-11, 1992.

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INFORMATION DISCLOSURE CITATION

Atty. Docket No.

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10/074,751

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